## Search Notes



| Application/Control No. | Applicant(s)/Patent Under<br>Reexamination |
|-------------------------|--|
| 10735696                | MAN-HAK TSO ET AL.                         |
| Examiner                | Art Unit                                   |
| Haile, Awet A           | 2416                                       |

|   | SE | ARC | HI | =D |
|---|----|-----|----|----|
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| Class | Subclass                     | Date      | Examiner   |
|-------|------------------------------|-----------|------------|
| 370   | 395                          | 6/9/2008  | Awet Haile |
| 370   | 382                          | 6/9/2008  | Awet Haile |
| 370   | 300                          | 6/9/2008  | Awet Haile |
| 370   | 389                          | 6/9/2008  | Awet Haile |
| 370   | 392                          | 6/9/2008  | Awet Haile |
| 370   | 378                          | 6/9/2008  | Awet Haile |
| 370   | 379                          | 6/9/2008  | Awet Haile |
| 370   | 381                          | 6/9/2008  | Awet Haile |
| 370   | 383                          | 6/9/2008  | Awet Haile |
| 370   | 395.7                        | 6/9/2008  | Awet Haile |
| Above | Updated                      | 1/12/2009 | Awet Haile |
| 370   | 527                          | 1/12/2009 | Awet Haile |
| 370   | 395.2                        | 1/12/2009 | Awet Haile |
| 370   | 351                          | 1/12/2009 | Awet Haile |
| 709   | 206, 224, 245, 203, 240, 207 | 1/12/2009 | Awet Haile |
| 707   | 100                          | 1/12/2009 | Awet Haile |

| SEARCH NOTES                |           |            |
|-----------------------------|-----------|------------|
| Search Notes                | Date      | Examiner   |
| East search                 | 6/9/2008  | Awet Haile |
| East(class and text search) | 1/12/2009 | Awet Haile |

| INTERFERENCE SEARCH |          |      |          |
|---------------------|----------|------|----------|
| Class               | Subclass | Date | Examiner |
|                     |          |      |          |

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U.S. Patent and Trademark Office Part of Paper No. :